- Amendment After Final Rejection -

F-878

IN THE SPECIFICATION

Please amend the originally-filed Specification as follows:

- (a) On page 1, underneath the Title (and above the "FIELD OF INVENTION" header), please insert:
 - -- BACKGROUND OF THE INVENTION --
- (b) On page 1, underneath the FIELD OF INVENTION header (and above the "BRIEF DESCRIPTION OF THE DRAWINGS"), please insert:
 - -- SUMMARY OF THE INVENTION
- [0001.1] The present invention is directed to a method that employs identification tags to determine the presence or absence of a part or sub assembly of a semiconductor process tool. The method includes attaching the identification tag to the part or sub assembly of the semiconductor processing tool, the identification tag including a passive resonant circuit that is responsive to radio frequency energy, and applying a radio frequency signal to the identification tag, which creates a measurable decrease in field strength in at least a portion of the radio frequency signal. The method further includes determining the presence or absence of the decrease in field strength, and determining the presence of the part or assembly based on the presence or absence of the decrease in field strength.
- [0001.2] The present invention is also directed to an apparatus that employs identification tags to determine the presence or absence of a part or sub assembly of a semiconductor process tool. The apparatus includes a part or assembly of a semiconductor processing tool and an identification tag attached to the part or assembly in which the tag includes a passive resonant circuit that is responsive to radio frequency energy of a particular frequency. The apparatus further includes that, upon application of the radio frequency energy to the identification tag, the identification tag creates a measurable decrease in field strength in at least a portion of the radio frequency energy at the particular frequency so that the presence or absence of the part or assembly may be determined from the presence or absence of the decreased field strength. --